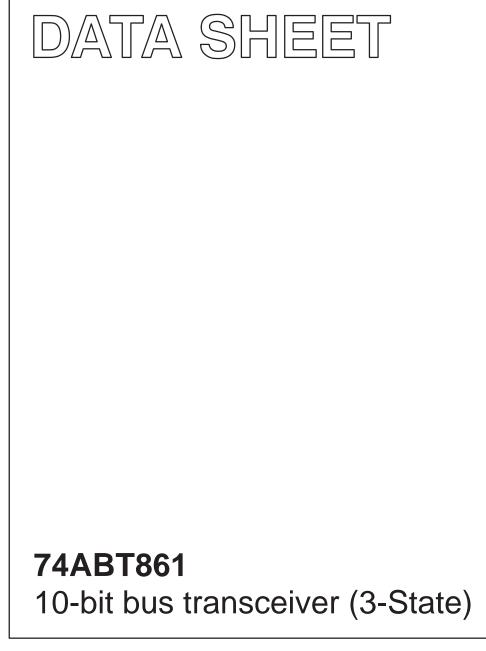
INTEGRATED CIRCUITS



Product specification Supersedes data of 1995 Sep 06 IC23 Data Handbook

1998 Jan 16



74ABT861

FEATURES

- Provides high performance bus interface buffering for wide data/address paths or buses carrying parity
- Buffered control inputs for light loading, or increased fan-in as required with MOS microprocessors
- Output capability: +64mA/-32mA
- Latch-up protection exceeds 500mA per Jedec Std 17
- ESD protection exceeds 2000 V per MIL STD 883 Method 3015 and 200 V per Machine Model
- Power-up 3-State
- Inputs are disabled during 3-State mode

DESCRIPTION

The 74ABT861 bus transceiver provides high performance bus interface buffering for wide data/address paths of buses carrying parity.

The 74ABT861 10-bit bus transceiver has NOR-ed transmit and receive output enables for maximum control flexibility.

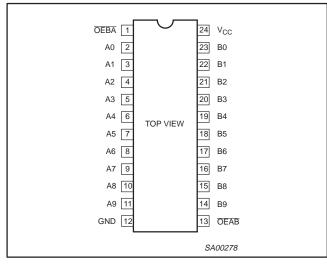
QUICK REFERENCE DATA

SYMBOL	PARAMETER	PARAMETER CONDITIONS T _{amb} = 25°C; GND = 0V			
t _{PLH} t _{PHL}	Propagation delay An to Bn or Bn to An	C _L = 50pF; V _{CC} = 5V	3.4	ns	
C _{IN}	Input capacitance	$V_I = 0V \text{ or } V_{CC}$	4	pF	
C _{I/O}	I/O capacitance	Outputs disabled; $V_O = 0V$ or V_{CC}	7	pF	
I _{CCZ}	Total supply current	Outputs disabled; V_{CC} =5.5V	500	nA	

ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
24-Pin Plastic DIP	–40°C to +85°C	74ABT861 N	74ABT861 N	SOT222-1
24-Pin plastic SO	–40°C to +85°C	74ABT861 D	74ABT861 D	SOT137-1
24-Pin Plastic SSOP Type II	–40°C to +85°C	74ABT861 DB	74ABT861 DB	SOT340-1
24-Pin Plastic TSSOP Type I	–40°C to +85°C	74ABT861 PW	74ABT861PW DH	SOT355-1

PIN CONFIGURATION

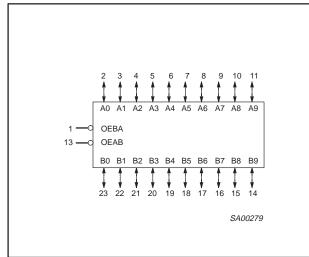


PIN DESCRIPTION

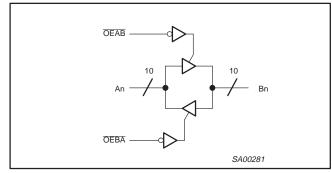
PIN NUMBER	SYMBOL	FUNCTION
13	OEAB	A side to B side output enable input (active-Low)
2, 3, 4, 5, 6, 7, 8, 9, 10, 11	A0-A9	Data inputs/outputs (A side)
23, 22, 21, 20, 19, 18, 17, 16, 15, 14	B0-B9	Data inputs/outputs (B side)
1	OEBA	B side to A side output enable input (active-Low)
12	GND	Ground (0V)
24	V _{CC}	Positive supply voltage

74ABT861

LOGIC SYMBOL



LOGIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +7.0	V
I _{IK}	DC input diode current	V ₁ < 0	-18	mA
VI	DC input voltage ³		-1.2 to +7.0	V
I _{OK}	DC output diode current	V _O < 0	-50	mA
V _{OUT}	DC output voltage ³	output in Off or High state	-0.5 to +5.5	V
I _{OUT}	DC output current	output in Low state	128	mA
T _{stg}	Storage temperature range		-65 to 150	°C

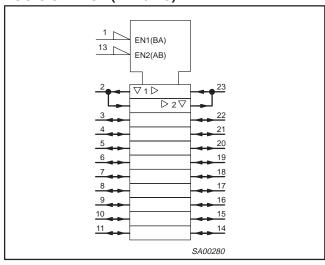
NOTES:

1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

2. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.

3. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

LOGIC SYMBOL (IEEE/IEC)



FUNCTION TABLE

INP	UTS	OPERATING
OEAB	OEBA	MODE
L	Н	A data to B bus
н	L	B data to A bus
н	Н	Z

= High voltage level н

Low voltage level L =

X = Don't care Z = High impedance "off" state

74ABT861

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIM	UNIT	
		Min	Мах	1
V _{CC}	DC supply voltage	4.5	5.5	V
VI	Input voltage	0	V _{CC}	V
VIH	High-level input voltage	2.0		V
V _{IL}	Low-level input voltage		0.8	V
I _{OH}	High-level output current		-32	mA
I _{OL}	Low-level output current		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	5	ns/V
T _{amb}	Operating free-air temperature range	-40	+85	°C

DC ELECTRICAL CHARACTERISTICS

						LIMITS			
SYMBOL	DL PARAMETER		TEST CONDITIONS		T _{amb} = +25°C			-40°C 85°C	
				Min	Тур	Max	Min	Max	
VIK	Input clamp vol	tage	$V_{CC} = 4.5V; I_{IK} = -18mA$		-0.9	-1.2		-1.2	V
			V_{CC} = 4.5V; I_{OH} = -3mA; V_I = V_{IL} or V_{IH}	2.5	3.5		2.5		V
V _{OH}	High-level outp	out voltage	V_{CC} = 5.0V; I_{OH} = -3mA; V_I = V_{IL} or V_{IH}	3.0	4.0		3.0		V
			V_{CC} = 4.5V; I_{OH} = -32mA; V_{I} = V_{IL} or V_{IH}	2.0	2.6		2.0		V
V _{OL}	Low-level outp	ut voltage	$V_{CC} = 4.5$ V; $I_{OL} = 64$ mA; $V_I = V_{IL}$ or V_{IH}		0.42	0.55		0.55	V
II.	Input leakage	Control pins	V _{CC} = 5.5V; V _I = GND or 5.5V		±0.01	±1.0		±1.0	μA
	current	Data pins	V _{CC} = 5.5V; V ₁ = GND or 5.5V		±5.0	±100		±100	μA
I _{OFF}	Power-off leaka	age current	V_{CC} = 0.0V; V_{O} or $V_{I}\ \leq4.5V$		±5.0	±100		±100	μA
I _{PU/PD}	Power–up/down 3-State output current ³		$V_{\underline{CC}} = 2.1V$; $V_{O} = 0.5V$; $V_{I} = GND$ or V_{CC} ; $V_{OE} = V_{CC}$		±5.0	±50		±50	μΑ
I _{IH} + I _{OZH}	3-State output	High current	$V_{CC} = 5.5V; V_{O} = 2.7V; V_{I} = V_{IL} \text{ or } V_{IH}$		5.0	50		50	μA
I _{IL} + I _{OZL}	3-State output	Low current	V_{CC} = 5.5V; V_{O} = 0.5V; V_{I} = V_{IL} or V_{IH}		-5.0	-50		-50	μA
I _{CEX}	Output high lea	kage current	V_{CC} = 5.5V; V_{O} = 5.5V; V_{I} = GND or V_{CC}		5.0	50		50	μA
Ι _Ο	Output current		$V_{CC} = 5.5V; V_{O} = 2.5V$	-50	-100	-180	-50	-180	mA
ICCH			V_{CC} = 5.5V; Outputs High, V_{I} = GND or V_{CC}		0.5	250		250	μA
I _{CCL}	Quiescent supp	oly current	V_{CC} = 5.5V; Outputs Low, V_{I} = GND or V_{CC}		25	38		38	mA
I _{CCZ}]		V_{CC} = 5.5V; Outputs 3-State; V ₁ = GND or V _{CC}		0.5	50		50	μΑ
			Outputs enabled, one input at 3.4V, other inputs at V _{CC} or GND; V _{CC} = $5.5V$		0.5	1.5		1.5	mA
ΔI_{CC}	Additional supply current per input pin ²		Outputs 3-State, one data input at 3.4V, other inputs at V_{CC} or GND; V_{CC} = 5.5V		0.01	50		50	μΑ
			Outputs 3-State, one enable input at 3.4V, other inputs at V_{CC} or GND; $V_{CC} = 5.5V$		0.5	1.5		1.5	mA

NOTES:

Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
This is the increase in supply current for each input at 3.4V.
This parameter is valid for any V_{CC} between 0V and 2.1V with a transition time of up to 10msec. For V_{CC} = 2.1V to V_{CC} = 5V ± 10%, a transition time of up to 100µsec is permitted.

74ABT861

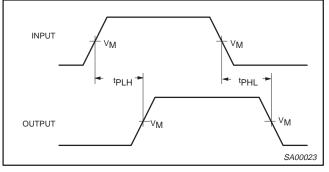
AC CHARACTERISTICS

GND = 0V, $t_R = t_F = 2.5 \text{ns}$, $C_L = 50 \text{pF}$, $R_L = 500 \Omega$

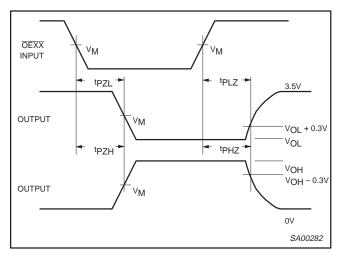
					LIMITS			
SYMBOL	PARAMETER	WAVEFORM	Ţ	- _{amb} = +25°(V _{CC} = +5.0V		+8	= -40 to 5°C .0V ±0.5V	UNIT
			Min	Тур	Max	Min	Max	
t _{PLH} t _{PHL}	Propagation delay An to Bn or Bn to An	1	1.1 1.0	3.4 3.2	4.9 4.9	1.1 1.0	5.2 5.2	ns
t _{PZH} t _{PZL}	Output enable time to High and Low level	2	1.2 2.4	3.5 4.6	5.0 6.0	1.2 2.4	5.9 6.9	ns
t _{PHZ} t _{PLZ}	Output disable time from High and Low level	2	3.1 3.7	5.3 5.3	6.5 6.6	3.1 3.7	7.5 7.1	ns

AC WAVEFORMS

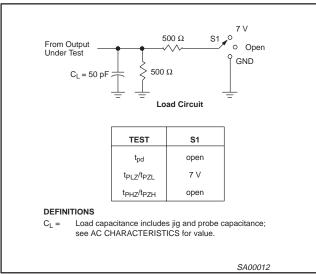
 V_{M} = 1.5V, V_{IN} = GND to 3.0V



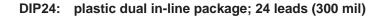
Waveform 1. Input to Output Propagation Delays

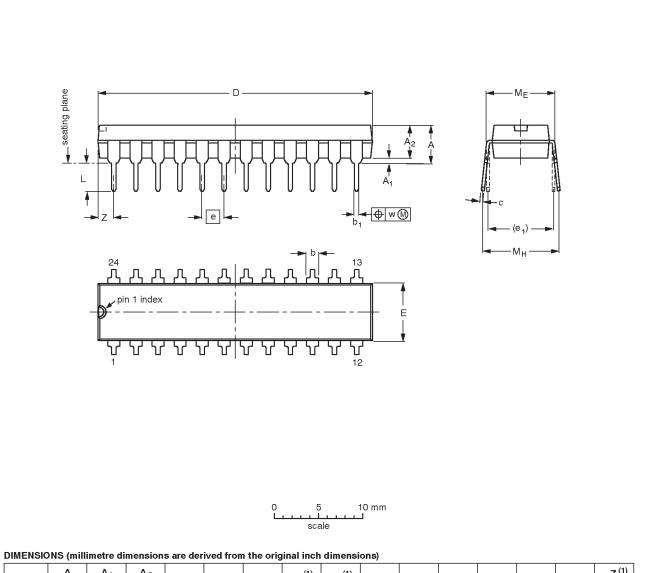


Waveform 2. 3-State Output Enable and Disable Times



TEST CIRCUIT AND WAVEFORM





UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	с	D ⁽¹⁾	E ⁽¹⁾	e	e ₁	L	ME	М _Н	w	Z ⁽¹⁾ max.
mm	4.70	0.38	3.94	1.63 1.14	0.56 0.43	0.36 0.25	31.9 31.5	6.73 6.48	2.54	7.62	3.51 3.05	8.13 7.62	10.03 7.62	0.25	2.05
inches	0.185	0.015	0.155	0.064 0.045	0.022 0.017	0.014 0.010	1.256 1.240	0.265 0.255	0.100	0.300	0.138 0.120	0.32 0.30	0.395 0.300	0.01	0.081

Note

1. Plastic or metal protrusions of 0.01 inches maximum per side are not included.

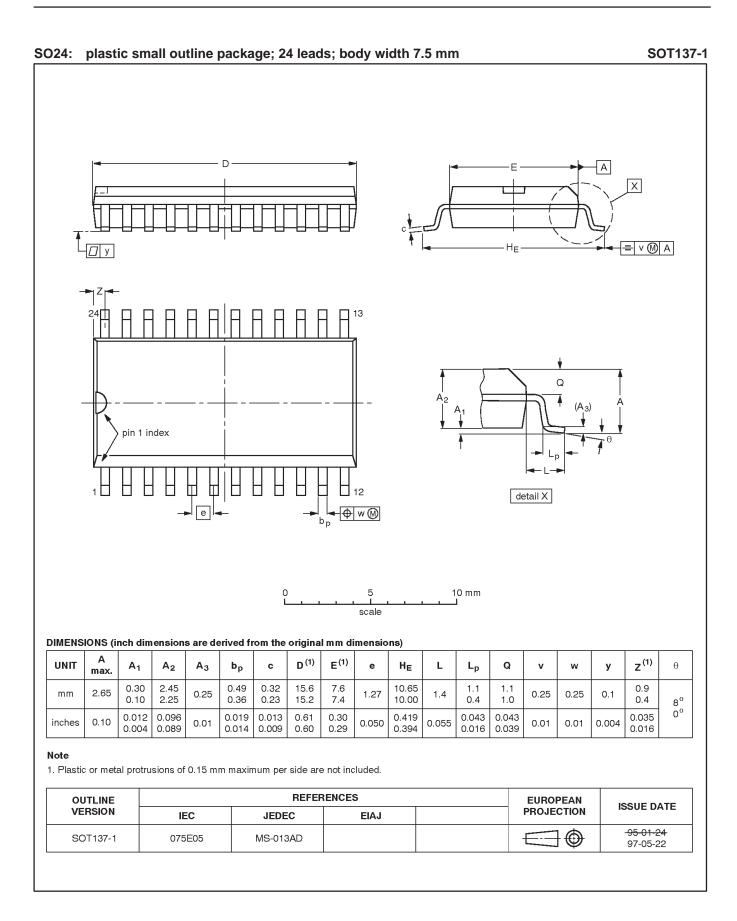
OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT222-1		MS-001AF				95-03-11

Product specification

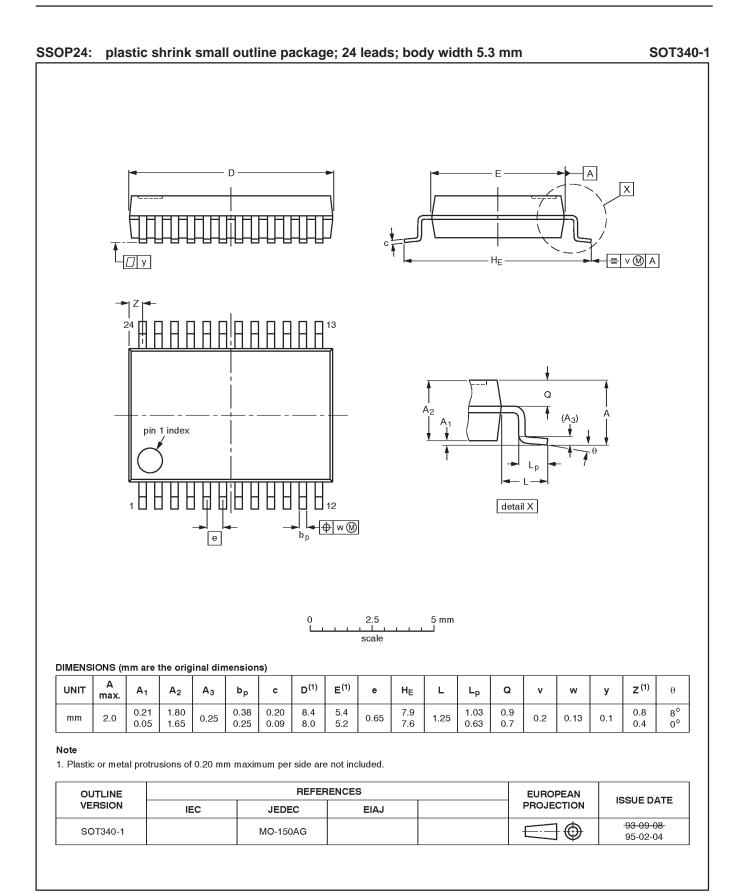
SOT222-1

74ABT861

74ABT861

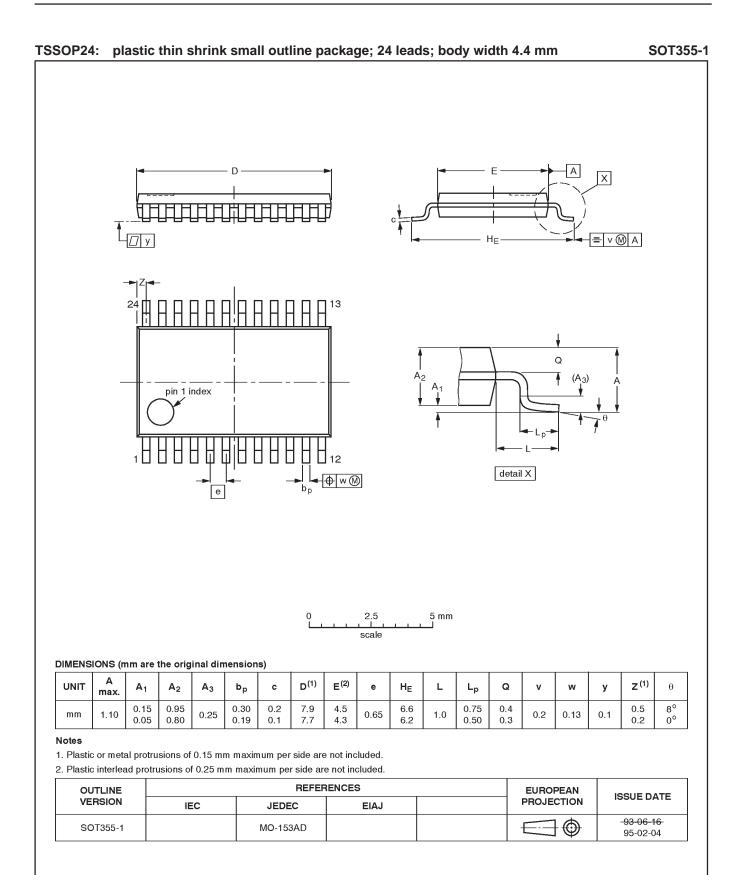


74ABT861



1998 Jan 16

74ABT861



74ABT861

Data sheet status

Data sheet status	Product status	Definition ^[1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

[1] Please consult the most recently issued datasheet before initiating or completing a design.

Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

Application information — Applications that are described herein for any of these products are for illustrative purposes only. Philips Semiconductors make no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Disclaimers

Life support — These products are not designed for use in life support appliances, devices or systems where malfunction of these products can reasonably be expected to result in personal injury. Philips Semiconductors customers using or selling these products for use in such applications do so at their own risk and agree to fully indemnify Philips Semiconductors for any damages resulting from such application.

Right to make changes — Philips Semiconductors reserves the right to make changes, without notice, in the products, including circuits, standard cells, and/or software, described or contained herein in order to improve design and/or performance. Philips Semiconductors assumes no responsibility or liability for the use of any of these products, conveys no license or title under any patent, copyright, or mask work right to these products, and makes no representations or warranties that these products are free from patent, copyright, or mask work right infringement, unless otherwise specified.

Philips Semiconductors 811 East Arques Avenue P.O. Box 3409 Sunnyvale, California 94088–3409 Telephone 800-234-7381 © Copyright Philips Electronics North America Corporation 1998 All rights reserved. Printed in U.S.A.

Document order number:

print code

Date of release: 05-96 9397-750-03476

Let's make things better.



